PCN Number:		20130708002				PCN Da	te:	07/11/2013				
Title:Qualification of TI Clark as an Additional Assembly, Bump, and Test site for Select Devices on WCSP and QFN Package												
Custom	er Contact:	PCI	NN	lanager	Phon	e: +1(214)480-6	6C)37	Dept:	ot: Quality Services		
Propose	ed 1 st Ship Da	te:		10/11/20	10/11/2013Estimated Sample Availability:				Date Provided at Sample request			
Change	Туре:											
Asse	embly Site			Assem	Assembly Process			Assembly	/ Mate	erials		
Desi	gn			Electric	cal Spe	cification			Mechanic	al Sp	ecification	
🛛 Test	Site			Packin	g/Shipp	bing/Labeling			Test Proc	ess		
🛛 Waf	er Bump Site			Wafer	Bump N	Material			Wafer Bu	imp P	rocess	
Waf	er Fab Site			Wafer	Fab Ma	terials			Wafer Fa	b Pro	cess	
					PC	N Details						
Descrip	tion of Chang	je:										
Group 1: WCSP current as			ssembly	sembly – JCAP-AT JCAP-AT			Cla	Clark-AT				
Bump Site				JCAP-FAB			CI	ark-E	3P			
Solder Ball					MA22	.22008110 42			20784	8		
Group 2: QFN current assembly – TIM. No Assembly material differences												
					1	TIM			TI	[Clai	<u>'k</u>	
Mold compound				420	J8625			42	208625			
Wire					0.96	smil Au		0.96 mil Au			Au	
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.												
Reason for Change:												
Continuity of supply.												
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):												
None	None											
L												

Changes to product identification resulting from this PCN:						
Assembly Site						
JCAP-AT	Assembly S	ite Origin (22L)	ASO: JCP			
TIM	Assembly S	ite Origin (22L)	ASO: MLA			
Clark-AT	Assembly S	ite Origin (22L)	ASO: QAB			
Sample product ship	ping label to show co	de location only	- not actual product label			
INSTRUMENTS Image in the						
Product Affected:						
Group 1 Device: WC	SP package					
TPS22913BYZVR	TPS22913BYZVT					
Group 2 : QFN packa	ge					
BQ27410DRZR-G1	BQ27510DRZR-G3					

 Qualification Data – Group 1 Device

 This qualification has been specifically developed for the validation of this change. The qualification
data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle : TPS22913BYZV (MSL1-260C)						
Package Construction Details						
Assembly & Bump Site: CLARK Bump Composition: SnAg						
# Pins-Designator, Family:	4-YZV, WCSP/DSBGA	Bump Diameter:		0.25mm		
Qualification: 🗌 Plan 🛛 Test Results						
Reliability Test	Conditions		Sample Size/Fail			
Electrical Characterization	-		30/0			
Manufacturability (Assembly)	(per mfg site specificatio	Pass				
Reference Qualification						

Qual Vehicle : TXS0104EYZTR (MSL1-260C)							
Package Construction Details							
Assembly & Bump Site:	CLARK	LARK Bump Co		SnAg	SnAgCu		
# Pins-Designator, Family:	12-YZT, WCSP/DSBGA	Bump	Diameter :	0.25m	0.25mm		
Qualification: 🗌 Plan 🛛 Test Results							
Poliability Test	Conditions		Sample Size/Fail				
Reliability Test			Lot 1	Lot 2	Lot 3		
**Steady-state Life Test	150C (300 Hrs)		77/0	77/0	77/0		
**High Temp. Storage Bake	150C (1000hrs)		77/0	77/0	77/0		
**Biased HAST	130C/85%RH (96 Hrs)		77/0	77/0	77/0		
**Unbiased HAST	130C/85%RH (96 Hrs)		77/0	77/0	77/0		
**Temperature Cycle	-55C/+125C (1000 Cyc)		77/0	77/0	77/0		
Manufacturability (Assembly)	(per mfg site specifications)		Pass	Pass	Pass		
** Note: Moisture Preconditioning (MSL1-260C)							

Qualification Data – Group 2 Device

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle : SN8034DRZ (MSL2-260C)							
Package Construction Details							
Assembly Site:	CLARK	Mold C	ompound:	42086	4208625		
# Pins-Designator, Family:	12-DRZ, QFN	Mount Compound:		42077	4207768		
Lead Finish, Base :	NiPdAu, Cu B		Bond Wire:	0.96m	0.96mil Au		
Qualification: 🗌 Plan 🛛 Test Results							
Poliability Test	Conditions		Sample Size/Fail				
Kellability Test			Lot 1	Lot 2	Lot 3		
**Autoclave	121C (96 Hrs)		77/0	77/0	77/0		
**High Temp. Storage Bake	170C (420hrs)		77/0	77/0	77/0		
**Temperature Cycle	-65C/+150C (500 Cyc)		82/0	82/0	82/0		
X-Ray	(top side only)		5/0	5/0	5/0		
Manufacturability (Assembly)	(per mfg site specifications)		Pass	Pass	Pass		
Moisture Sensitivity	MSL2-260C		12/0	12/0	12/0		
** Moisture Preconditioning (MSL2-260C)							

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com